

FEATURES

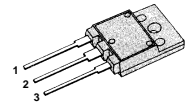
- Avalanche Rugged Technology
- Rugged Gate Oxide Technology
- Lower Input Capacitance
- Improved Gate Charge
- Extended Safe Operating Area
- Lower Leakage Current: 25µA (Max.) @ $V_{DS} = 800V$
- Lower $R_{DS(ON)}$: 1.000Ω (Typ.)

$$BV_{DSS} = 800V$$

$$R_{DS(ON)} = 1.5\Omega$$

$$I_D = 8A$$

TO-3P



1. Gate 2. Drain 3. Source

ABSOLUTE MAXIMUM RATINGS

Symbol	Characteristics	Value	Units
V_{DSS}	Drain-to-Source Voltage	800	V
I_D	Continuous Drain Current ($T_C = 25^\circ C$)	8	A
	Continuous Drain Current ($T_C = 100^\circ C$)	5.1	
I_{DM}	Drain Current-Pulsed ①	32	A
V_{GS}	Gate-to-Source Voltage	± 30	V
E_{AS}	Single Pulsed Avalanche Energy ②	444	mJ
I_{AR}	Avalanche Current ①	8	A
E_{AR}	Repetitive Avalanche Energy ①	24	mJ
dv/dt	Peak Diode Recovery dv/dt ③	2.0	V/ns
P_D	Total Power Dissipation ($T_C = 25^\circ C$)	240	W W/ $^\circ C$
	Linear Derating Factor	1.92	
T_J, T_{STG}	Operating Junction and Storage Temperature Range	-55 to +150	$^\circ C$
T_L	Maximum Lead Temp. for Soldering Purposes, 1/8" from case for 5-seconds	300	

THERMAL RESISTANCE

Symbol	Characteristics	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	0.52	$^\circ C/W$
$R_{\theta CS}$	Case-to-Sink	0.24	—	
$R_{\theta JA}$	Junction-to-Ambient	—	40	

ELECTRICAL CHARACTERISTICS ($T_C = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Characteristics	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-Source Breakdown Voltage	800	—	—	V	$V_{GS}=0V$, $I_D=250\mu A$
$\Delta BV/\Delta T_J$	Breakdown Voltage Temp. Coeff.	—	0.96	—	V/ $^\circ\text{C}$	$I_D=250\mu A$, See Fig 7
$V_{GS(th)}$	Gate Threshold Voltage	2.0	—	3.5	V	$V_{DS}=5V$, $I_D=250\mu A$
I_{GSS}	Gate-Source Leakage, Forward	—	—	100	nA	$V_{GS}=30V$
	Gate-Source Leakage, Reverse	—	—	–100		$V_{GS}= -30V$
I_{DSS}	Drain-to-Source Leakage Current	—	—	25	μA	$V_{DS}=800V$
		—	—	250		$V_{DS}=640V$, $T_C=125^\circ\text{C}$
$R_{DS(on)}$	Static Drain-Source On-State Resistance	—	—	1.5	Ω	$V_{GS}=10V$, $I_D=4A$ ④
g_{fs}	Forward Transconductance	—	6.56	—	S	$V_{DS}=50V$, $I_D=4A$ ④
C_{iss}	Input Capacitance	—	2020	2600	pF	$V_{GS}=0V$, $V_{DS}=25V$ $f=1\text{MHz}$ See Fig 5
C_{oss}	Output Capacitance	—	195	230		
C_{rss}	Reverse Transfer Capacitance	—	82	95		
$t_{d(on)}$	Turn-On Delay Time	—	25	60	ns	$V_{DD}=400V$, $I_D=9A$ $R_G=10\Omega$ See Fig 13 ④ ⑤
t_r	Rise Time	—	37	85		
$t_{d(off)}$	Turn-Off Delay Time	—	113	235		
t_f	Fall Time	—	42	95		
Q_g	Total Gate Charge	—	93	120	nC	$V_{DS}=640V$, $V_{GS}=10V$ $I_D=9A$ See Fig 6 & Fig 12 ④ ⑤
Q_{gs}	Gate-Source Charge	—	14.3	—		
Q_{gd}	Gate-Drain (Miller) Charge	—	42.1	—		

SOURCE-DRAIN DIODE RATINGS AND CHARACTERISTICS

Symbol	Characteristics	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current	—	—	8	A	Integral reverse pn-diode in the MOSFET
I_{SM}	Pulsed-Source Current ①	—	—	32		
V_{SD}	Diode Forward Voltage ④	—	—	1.4	V	$T_J=25^\circ\text{C}$, $I_S=8A$, $V_{GS}=0V$
t_{rr}	Reverse Recovery Time	—	560	—	ns	$T_J=25^\circ\text{C}$, $I_F=9A$ $di_F/dt=100A/\mu s$ ④
Q_{rr}	Reverse Recovery Charge	—	8.4	—	μC	

Notes:

- ① Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature
 ② $L=13\text{mH}$, $I_{AS}=8A$, $V_{DD}=50V$, $R_G=27\Omega$, Starting $T_J=25^\circ\text{C}$
 ③ $I_{SD} \leq 9A$, $di/dt \leq 180A/\mu s$, $V_{DD} \leq BV_{DSS}$, Starting $T_J=25^\circ\text{C}$
 ④ Pulse Test: Pulse Width $\leq 250\mu s$, Duty Cycle $\leq 2\%$
 ⑤ Essentially Independent of Operating Temperature

Fig 1. Output Characteristics

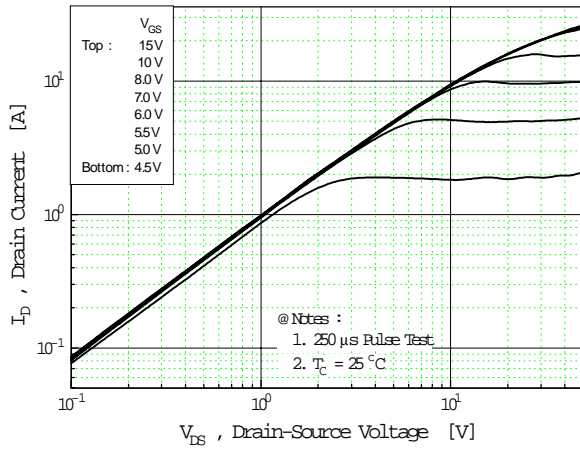


Fig 2. Transfer Characteristics

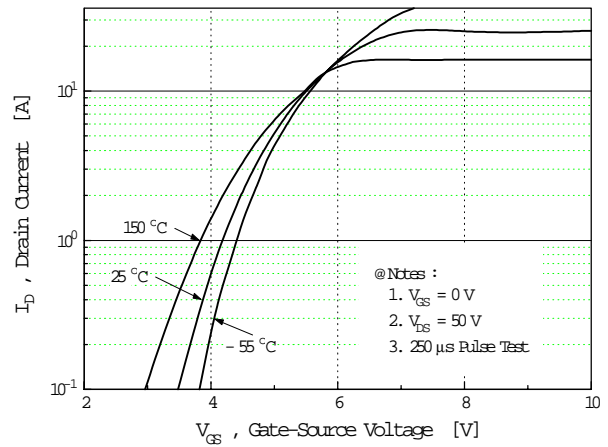


Fig 3. On-Resistance vs. Drain Current

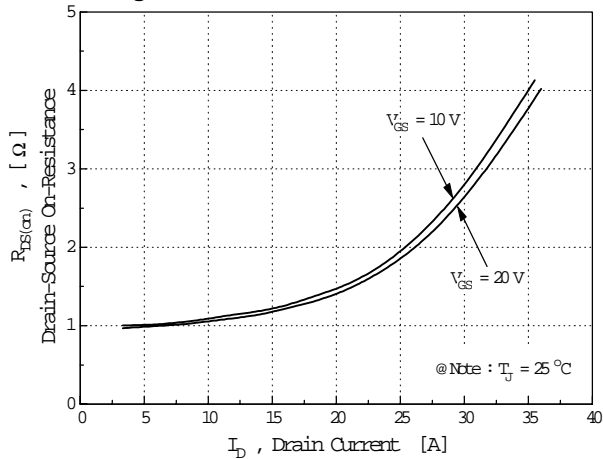


Fig 4. Source-Drain Diode Forward Voltage

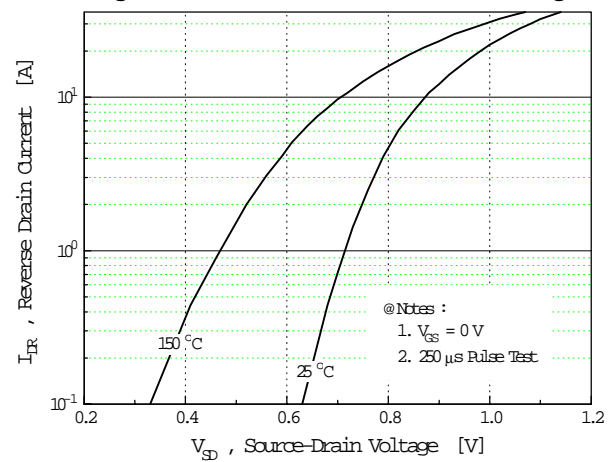


Fig 5. Capacitance vs. Drain-Source Voltage

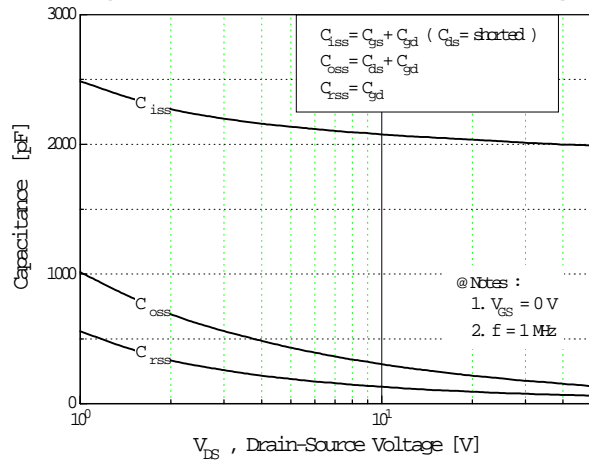


Fig 6. Gate Charge vs. Gate-Source Voltage

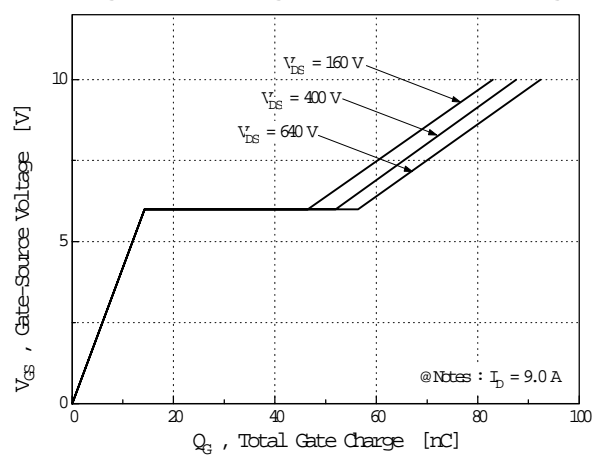


Fig 7. Breakdown Voltage vs. Temperature

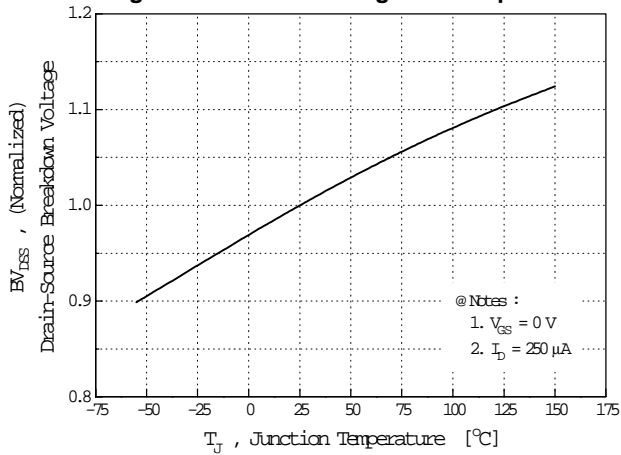


Fig 8. On-Resistance vs. Temperature

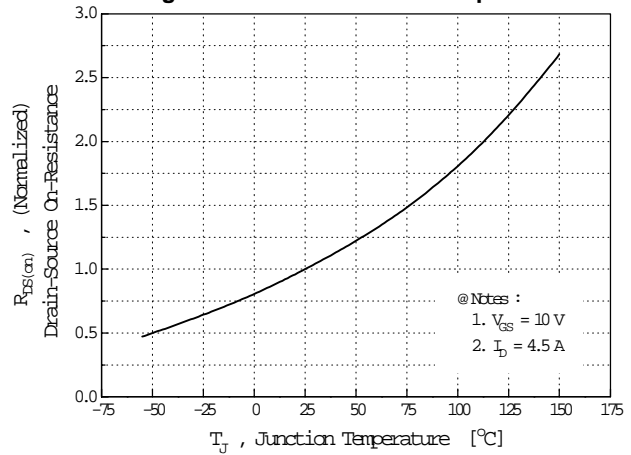


Fig 9. Max. Safe Operating Area

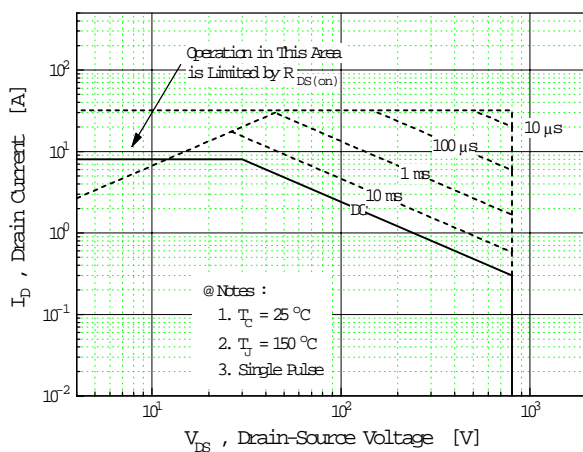


Fig 10. Max. Drain Current vs. Case Temperature

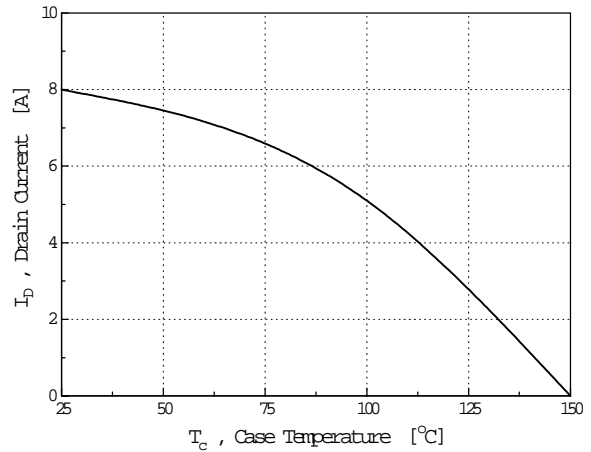


Fig 11. Thermal Response

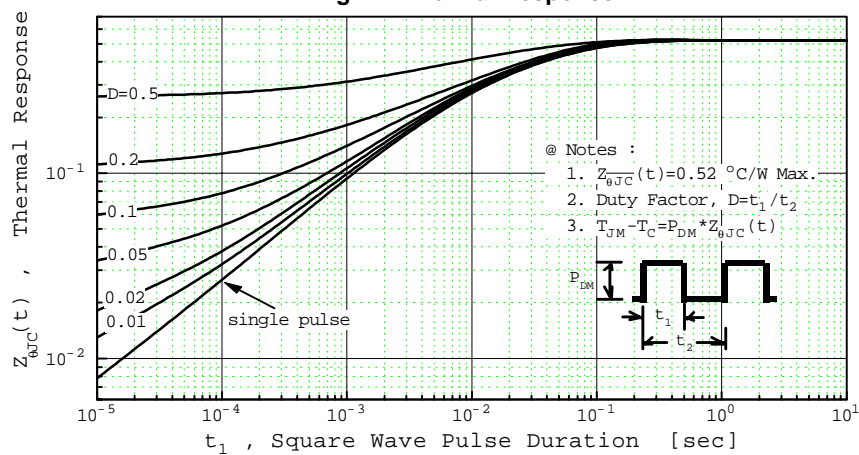


Fig 12. Gate Charge Test Circuit & Waveform

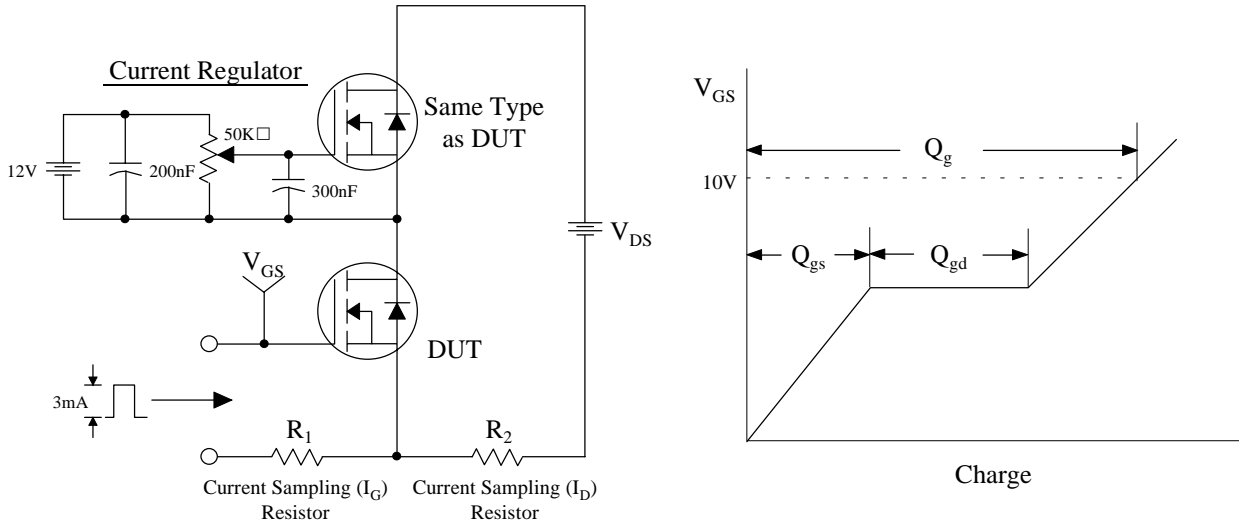


Fig 13. Resistive Switching Test Circuit & Waveforms

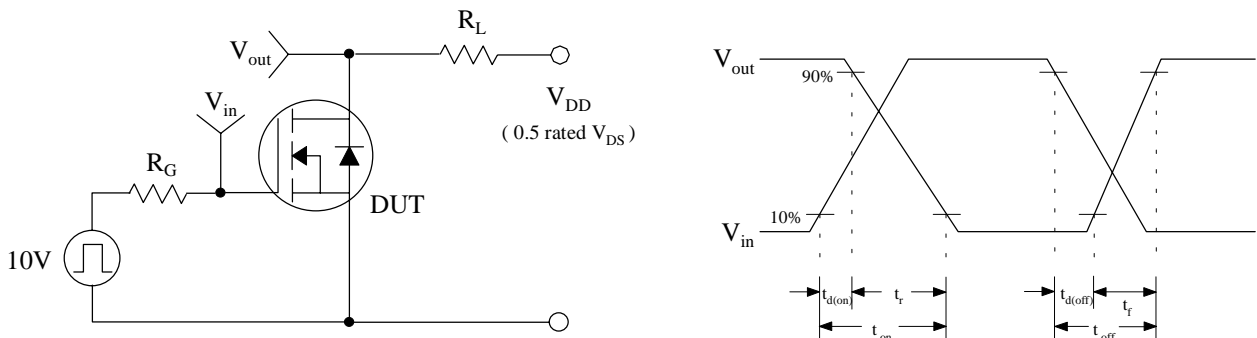
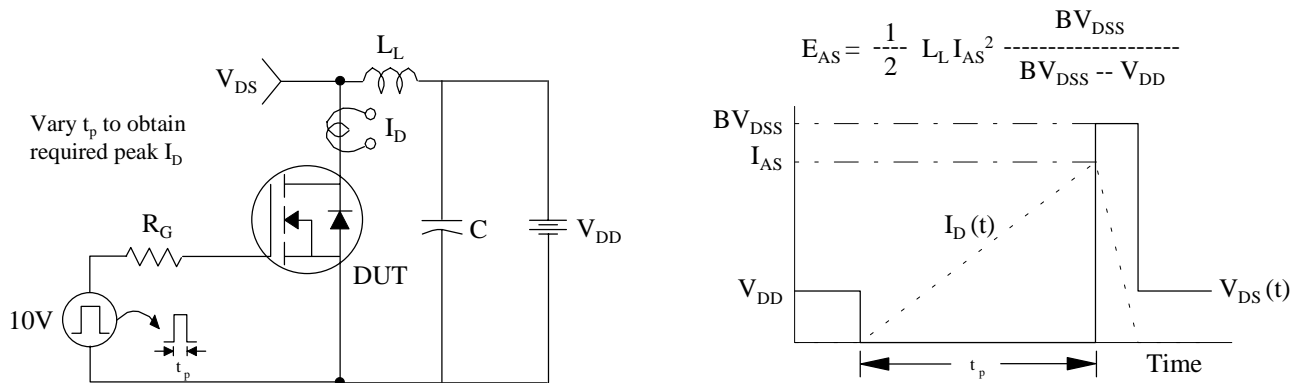
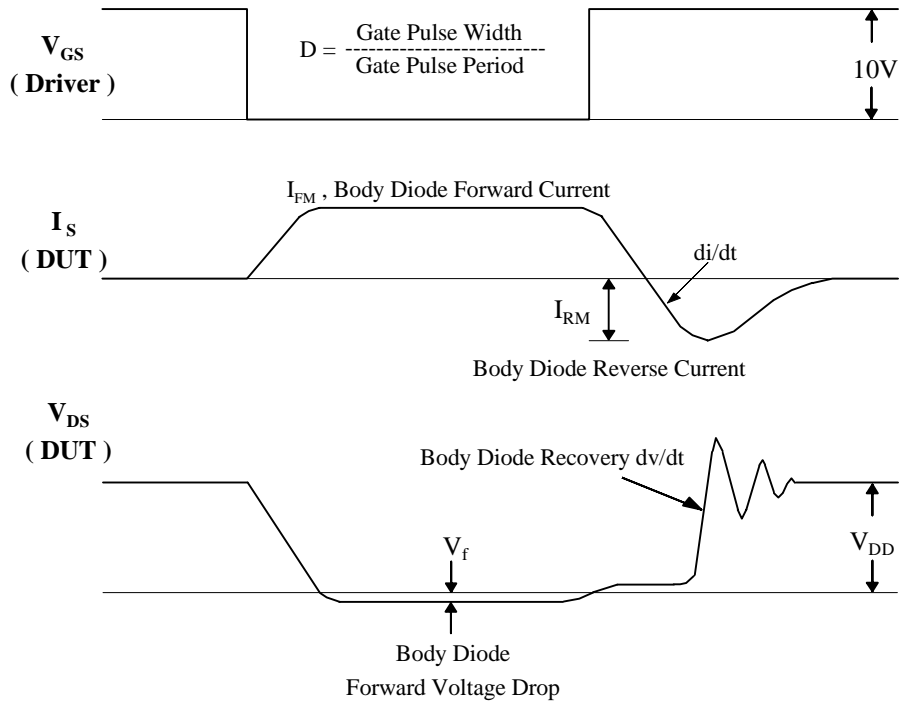
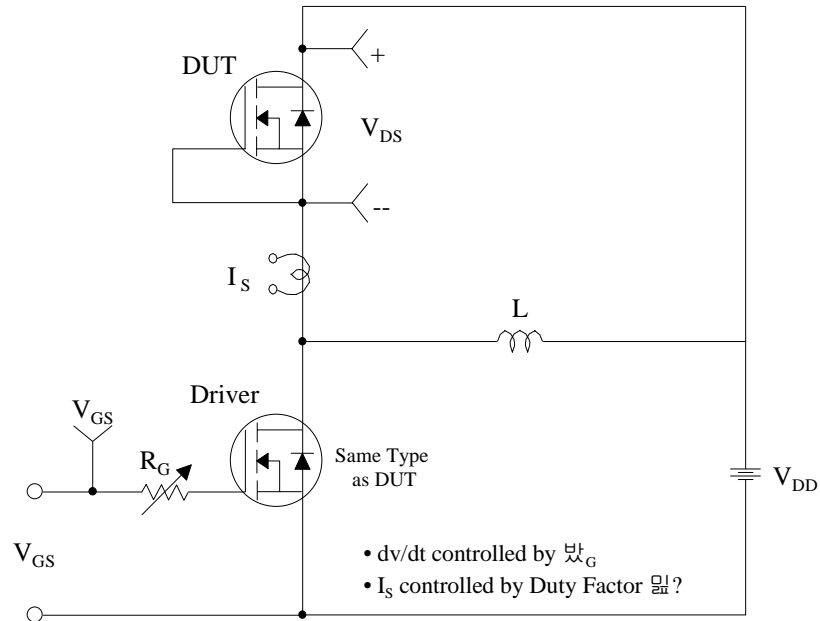


Fig 14. Unclamped Inductive Switching Test Circuit & Waveforms

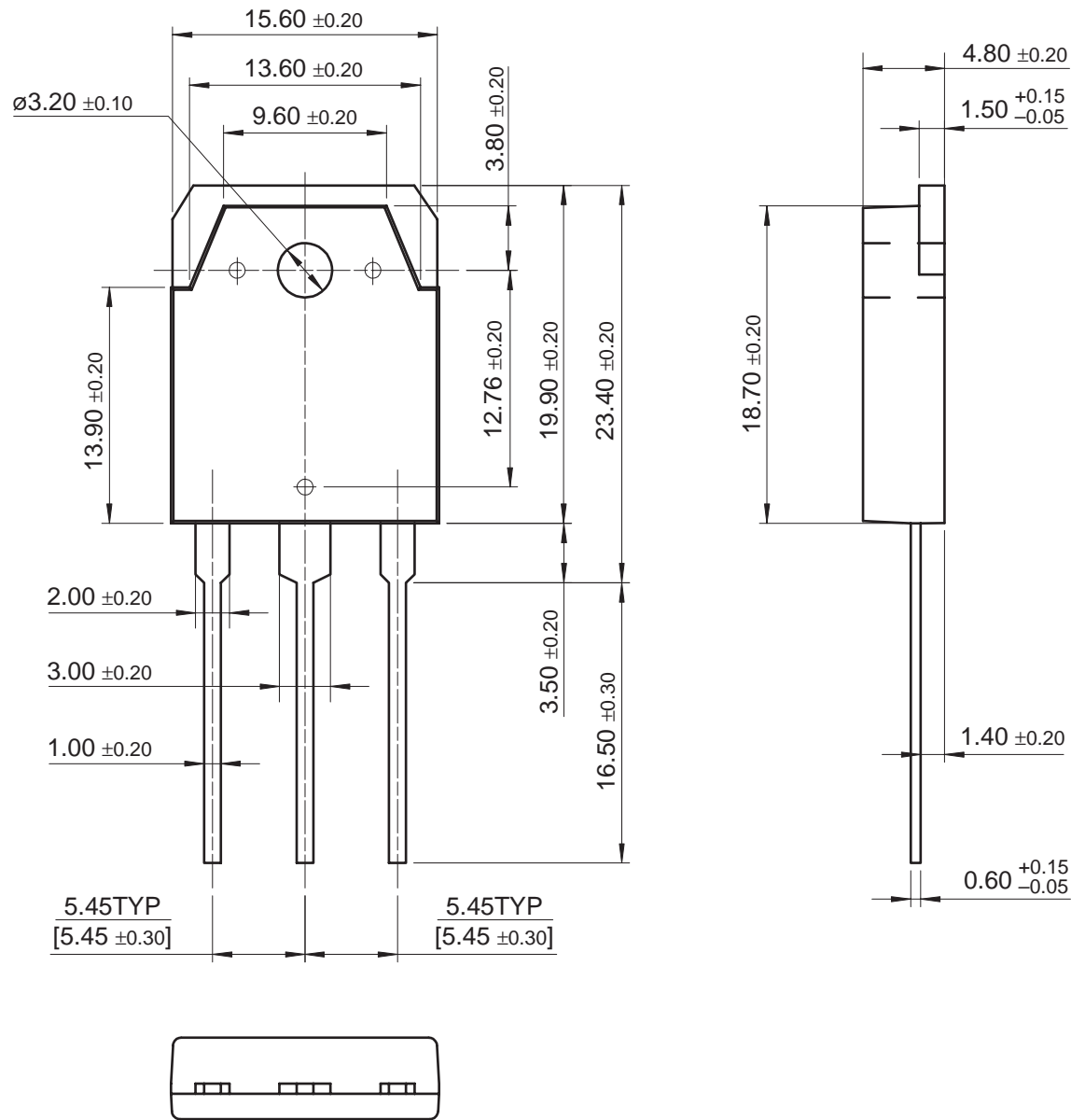




TO-3P Package Dimensions



TO-3P (FS PKG CODE AF)



Dimensions in Millimeters

August 1999, Rev B

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